

<b>Specification</b>	<b>AXIOM145ULN</b>	Rev.: 5	Date: 2021-10-13
----------------------	--------------------	---------	------------------

**Oscillator type: Ultra-Low Noise OCXO in SMD package with Oscillator Enable (OEN) and Oven Alarm (OA)**

Parameter	min.	typ.	max.	Unit	Condition
<b>Nominal frequency</b>	10.000			MHz	
<b>Frequency stability</b>					
Initial tolerance @ +25°C			±100	ppb	V <sub>c</sub> @ VREF/2
vs. operating temperature range	Option 2 & 3 See tables 2 & 3				steady state
vs. supply voltage variation (pushing)			±0.5	ppb	V <sub>s</sub> ±5 %
vs. load change (pulling)			±0.5	ppb	R <sub>L</sub> ±5 %
Long term (aging) per day			±0.5	ppb	after 10 days operation
Long term (aging) 1 <sup>st</sup> year			±50	ppb	after 10 days operation
Long term (aging) 15 years			±500	ppb	after 10 days operation
<b>Frequency adjustment range</b>					
Electronic Frequency Control (EFC)	±0.5	±1.0	±1.5	ppm	(Note 2)
EFC voltage V <sub>c</sub>	0	VREF/2	VREF	V	
EFC slope	Positive				
EFC input impedance	100			kΩ	
<b>RF output</b>					
Signal waveform	Sine wave				
Load R <sub>L</sub>	50			Ω	±5 %
Output level	+12	+14	+16	dBm	
Harmonics		-40	-30	dBc	
Spurious			-90	dBc	
Warm-up time @ +25°C			5	min	Δf <sub>final</sub> /f <sub>nominal</sub> < ±100 ppb
Phase noise	See table 1				Option 1
<b>Short term stability (Allan deviation)</b>		2·10 <sup>-12</sup> 2·10 <sup>-12</sup> 5·10 <sup>-12</sup>	5·10 <sup>-12</sup> 1·10 <sup>-11</sup> 5·10 <sup>-11</sup>		τ = 1 s τ = 10 s τ = 100 s
<b>Oven alarm output (OA)</b>	2.4	0 5	0.4	V V	Low = Alarm (Not stable) High = Oven Ready
<b>Oscillator enable input (OEN) (Note 3)</b>	2.4	0	0.4 V <sub>s</sub>	V V	Low = Oscillator OFF High = Oscillator ON
<b>Reference voltage VREF output</b>		5.0		V	
<b>Supply voltage V<sub>s</sub></b>	11.4	12.0	12.6	V	
<b>Current consumption (steady state)</b>			200	mA	@ +25°C
<b>Current consumption (warm-up)</b>			350	mA	
<b>Enclosure (see drawing) (LxWxH)</b>	41x30x16 max.			mm	
<b>Weight</b>			30	g	
<b>Packing</b>	Palette				

**Notes:**

1. Terminology and test conditions are according to IEC60679-1 and MIL-PRF-55310, unless otherwise stated
2. Tuning range sufficient to compensate for 15 years aging
3. HCMOS/TTL compatible input

**Absolute Maximum Ratings**

Parameter	min.	max.	Unit	Condition
Supply Voltage $V_s$	-0.5	$V_s + 10\%$	V	$V_s$ to GND
Control Voltage $V_c$	-0.5	15	V	$V_c$ to GND
Oscillator Enable Voltage $V_{OE}$	-0.5	$V_s$	V	$V_{OE}$ to GND
Storage Temperature	-55	+105	°C	
Resistance to Soldering Heat		10	sec	@ +245°C

**Phase Noise – Option 1:**

Offset	Option			Unit
	A	B	C	
1 Hz	-110	-112	-115	dBc/Hz
10 Hz	-140	-141	-142	dBc/Hz
100 Hz	-154	-156	-158	dBc/Hz
1 kHz	-163	-163	-163	dBc/Hz
≥10 kHz	-165	-165	-165	dBc/Hz
Noise floor	typ. -170			dBc/Hz

Table 1

**Frequency stability vs. temperature – Options 2 & 3**

Option 2	Stability [ppb]
05	±5
10	±10
25	±25

Table 2

Lower Temperature		Upper Temperature	
Option 3	T [°C]	Option 3	T [°C]
0	0	A	+50
1	-10	B	+60
2	-20	C	+70
3	-30	D	+75

Table 3

Standard: "1B" = -10°C to +60°C

**Ordering Code**

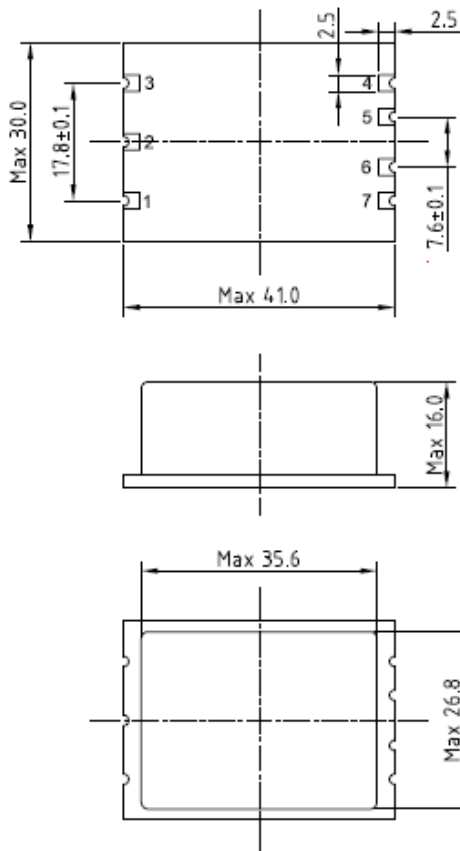
Model	Option 1 [Phase noise]	Option 2 [Stability]	Option 3 [Temperature range]	Revision	Frequency [MHz]
AXIOM145ULN	Table 1	Table 2	Table 3	Rev.5	10.000

Example: AXIOM145ULN-A-10-1B\_Rev.5 – 10.000 MHz

**Handling and Testing**

Parameter	Procedure	Source
Handling and Testing	Application Note AXAN-011	www.axtal.com
Processing	Application Note AXAN-012	www.axtal.com
Parameter	Procedure	Condition
Electrostatic discharge (ESD)		
THD devices	IEC60749-26	HBM 2000 V
SMD devices	IEC60749-27	MM 200 V
Washable	<input checked="" type="checkbox"/> Yes <input type="checkbox"/> No	
RoHS- Compliant	<input checked="" type="checkbox"/> Yes <input type="checkbox"/> No	

Enclosure drawing:



Pin connections

Pin #	Symbol	Function
1	RF OUT	RF Output
2	OA	Oven Alarm Output
3	GND	Ground
4	VREF	Reference Voltage
5	V <sub>c</sub>	Control Voltage (EFC)
6	OEN	Oscillator Enable Input
7	V <sub>s</sub>	Supply Voltage

Environmental conditions

Test	IEC 60068 Part ...	IEC 60679-1 Clause	MIL-STD-202G Method	MIL-STD-810F Method	MIL-PRF-55310D Clause	Test conditions (IEC)
Sealing tests (if applicable)	2-17	5.6.2	112E		3.6.1.2	Gross leak: Test Qc, Fine leak: Test Qk
Solderability	2-20	5.6.3	208H		3.6.52	Test Ta Method 1
Resistance to soldering heat	2-58		210F		3.6.48	Test Td <sub>1</sub> Method 2 Test Td <sub>2</sub> Method 2
Shock	2-27	5.6.8	213B	516.4	3.6.40	Test Ea, 3 x per axes 100g, 6 ms half-sine pulse
Vibration, sinusoidal	2-6	5.6.7.1	201A 204D	516.4-4	3.6.38.1 3.6.38.2	Test Fc, 30 min per axes, 10 Hz - 55 Hz 0,75mm; 55 Hz - 2 kHz, 10g
Vibration, random	2-64	5.6.7.3	214A	514.5	3.6.38.3 3.6.38.4	Test Fdb
Endurance tests			108A			
- ageing		5.7.1			4.8.35	30 days @ 85°C, OCXO @25°C
- extended aging		5.7.2				1000h, 2000h, 8000h @85°C

Other environmental conditions on request

Data sheet is for information purposes only and may be subject to modifications or may be discontinued without notice.

**Revision History**

Rev.	Drawing	Date [dd.mm.yyyy]	Remarks	Author	Checked
1	D0	10.12.2013	First issue preliminary version AXIOM15ULN	HH	BN
2	D0	12.12.2013	Changes: operating temp rang, supply voltage. Added: modulation bandwidth	HH	BN
1	D0	03.02.2014	New package, new P/N AXIOM145ULN	HH	BN
1	D1	16.01.2015	Editorial changes, environmental changes updated	HH	HH
2	D0	11.01.2016	Phase noise options added	HH	HH
3	D0	07.01.2017	Temperature stability options added	BN	BN
4	D0	15.08.2019	Various parameters updated, editorial changes	HH	HH
5	D0	13.10.2021	Phase noise options updated	HH	HH